

at least one opto-electronic transducer each connected to one of said plurality of nodes, each transducer including a means for generating an electrical output signal in response to an optical input signal from one of said nodes; and

a second means for determining a relative value of said electrical output signal, wherein said second means outputs a second electrical signal as an error signal when said relative value of said electrical signal is less than a predetermined value.

7. A method for determining errors in data transmission among a plurality of nodes connected to one another, said method comprising the steps of:

providing at least one optical module for converting an input optical signal from one of said nodes to an output electrical signal;

determining a relative value of said output electrical signal;

comprising said relative value to a base value; and outputting an error signal when said relative value is less than said base value.

8. The method according to Claim 7, wherein said error signal is stored in a memory.

WHAT IS CLAIMED IS:

1. Data bus for a plurality of nodes that are connected to one another via a star coupler, characterized in that said nodes are connected to optoelectric transducers via an optical transmission segment, said transducers being connected on the load side or on the line side and being situated on said star coupler, that said transducers generate input signals of said star coupler in electrical form, and that said transducers determine the change and/or the absolute value of the electrical useful signal and output an electrical signal to said star coupler when there is a deviation by a given magnitude.
2. Data bus according to Claim 1, characterized by a memory element for the signal of the individual optoelectric transducer.
3. Data bus according to Claim 1, characterized in that the memory element is addressable.
4. Data bus according to Claim 1 or 2, characterized in that the status of the memory element can be read out.
5. Data bus according to one of Claims 1 through 3, characterized in that the memory elements can be reset.